Vinylidenedithiophenmethyleneoxindole: A Centrosymmetric Building block for Donor–Acceptor Copolymers

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1. Thermogravimetric analysis (TGA) of VDTOI-based monomer 4 and copolymers.



Figure S1. TGA traces of VDTOI-based monomer 4 and copolymers.



Figure S2. DSC traces of VDTOI-based copolymers. 没有给出单体 4 的

2. Electrochemical properties of the VDTOI-based copolymers.



Figure S3. CV traces of the VDTOI-based copolymers.

3. The device performance of the **P2**-based FETs.



Figure S4. Typical transfer curves of the P2-based FETs.



Figure S5. Typical output curves of the P2-based FETs.

4. AFM topography images of the **VDTOI**-based copolymers.



Figure S6. AFM topography images of the **P1** thin films on PTS-modified SiO₂/Si substrates. (a) As-fabricated film and (b) After annealed at 140 °C for 5 min. All images are 5 μ m × 5 μ m in size.



Figure S7. AFM topography images of the P2 thin films on PTS-modified SiO₂/Si substrates. (a) As-fabricated film and (b) After annealed at 140 °C for 5 min. All images are 5 μ m × 5 μ m in size.

5. A2D-GXRD pattern of the P2 thin films,



Figure S8. 2D-GXRD pattern of of the P2 thin films on PTS -modified SiO_2/Si substrates after annealing at 140 °C for 5 min.